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Supporting Information

Studies on cyclization reactions of

3-amino-2,4-dihydroxybutanoic acid derivatives

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Crystallographic data of compounds (15a, 17a, 20a)	S22

Copies of ¹H and ¹³C NMR spectra

Compound 4a/4b



Compound 5a/5b



Compound 6a





Compound 6b





Compound 7a/7b



Compound 8a





Compound 9a/9b



Compound 10a/10b





Compound 11a/11b





Compound 12a/12b





Compound 13a/13b





Compound 14a/14b





Compound 15a





Compound 15b



Compound 16a/16b





Compound 17a



Compound 17b





Compound 18a



Compound 19a





Compound 20a





Crystallographic Data

X-ray diffraction data for compounds **15a**, **17a** and **20a** were collected by using a VENTURE PHOTON100 CMOS Bruker diffractometer with Micro-focus IuS source $Mo_{K\alpha}$ radiation. Crystals were mounted on a CryoLoop (Hampton Research) with Paratone-N (Hampton Research) as cryoprotectant and then flash-frozen in a nitrogen gas stream at 100 K. The temperature of the crystals was maintained at the selected value (100 K) by means of a N-Helix device cooling within an accuracy of ±1 K. The data were corrected for Lorentz polarization and absorption effects. The structures were solved by direct methods using SHELXS-97¹ and refined against F^2 by full-matrix least-squares techniques using SHELXL-2016² with anisotropic displacement parameters for all non-hydrogen atoms. Hydrogen atoms were located on a difference Fourier map and introduced into the calculations as a riding model with isotropic thermal parameters. All calculations were performed by using the Crystal Structure crystallographic software package WINGX.³

ORTEP drawings are shown in Figures S1, S2 and S3. The crystal data collection and refinement parameters are given in Table S1. CCDC 1520833, 1520834 and 1520835 contain the supplementary crystallographic data for this study. These data can be obtained free of charge from the Cambridge Crystallographic Data Centre via <u>http://www.ccdc.cam.ac.uk/Community/Requestastructure</u>.



Fig. S1. An ORTEP drawing of compound 15a. Thermal ellipsoids are shown at the 30% level.

Sheldrick, G. M. SHELXS-97, Program for Crystal Structure Solution, University of Göttingen, Göttingen, Germany, 1997.

²⁾ G. M. Sheldrick, Acta Crystallogr., Sect. A: Found. Crystallogr., 2008, 64, 112-122

³⁾ Farrugia, L. J. J. Appl. Cryst., 1999, 32, 837.



Fig. S2. An ORTEP drawing of compound 17a. Thermal ellipsoids are shown at the 30% level.



Fig. S3. An ORTEP drawing of compound 20a. Thermal ellipsoids are shown at the 30% level.

Table S1. Crystallographic data and structure refinement details.

Compound	15 a	17a	20a
Empirical formula	C ₁₀ H ₁₃ N O ₇	C ₁₉ H ₂₇ N O ₆ Si	C ₁₂ H ₉ N O ₅
M _r	259.21	393.50	247.20
Crystal size, mm	$0.09 \times 0.05 \times 0.01$	$0.12 \times 0.11 \times 0.08$	$0.13 \times 0.07 \times 0.01$
Crystal system	monoclinic	monoclinic	monoclinic
Space group	P 2 ₁	P 2 ₁	P 2 ₁
a, Å	6.0454(6)	8.1774(4)	8.2084(14)
b, Å	14.0347(14)	8.2158(3)	5.2477(8)
c, Å	7.1416(8)	15.0345(7)	24.351(4)
α, °	90	90	90
β, °	101.033(3)	98.231(2)	90.768(5)
γ, °	90	90	90
Cell volume, Å ³	594.73(11)	999.67(8)	1048.8(3)
Z ; Z'	2;1	2;1	4;2
T, K	100(1)	100(1)	100(1)
Radiation type ; wavelength Å	ΜοΚα ; 0.71073	ΜοΚα ; 0.71073	ΜοΚα ; 0.71073
F ₀₀₀	272	420	512
μ, mm ⁻¹	0.124	0.152	0.124
θ range, °	2.903 - 30.409	2.517 - 30.554	2.481 - 26.435
Reflection collected	20 042	42 103	20 958
Reflections unique	3 515	6 114	4 289
R _{int}	0.0943	0.0235	0.0587
GOF	1.062	1.055	1.159
Refl. obs. $(I > 2\sigma(I))$	2 242	5 766	3 895
Parameters	166	252	202
Flack parameter	0.1(4)	0.03(2)	0.9(6)
wR ₂ (all data)	0.3029	0.0635	0.3717
R value $(I > 2\sigma(I))$	0.1101	0.0254	0.1518
Largest diff. peak and hole (e ⁻ .Å ⁻³)	1.060 ; -0.377	0.260 ; -0.226	1.245 ; -0.734